

## Test Probes

### KLEPS 1 MICRO Series

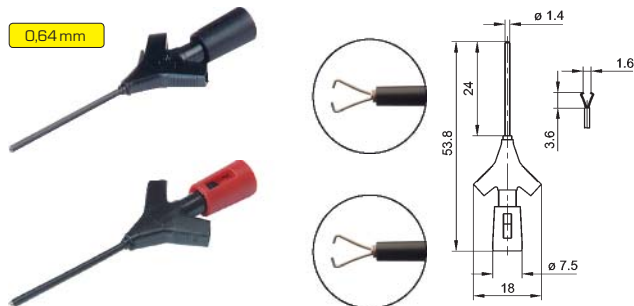
Miniature clamp-type test probe with rotating grip jaws (SMD technology). The insulated shaft can be bent up to 35°. Suitable for very thin wires and densely packed contact points (1.27 mm IC spacing pitch).

Max. current 2A

Contact resistance 10mΩ

Temperature range: -25°C to +100°C

Connects with MKL 0,64/25-0,64 or MAL 4-0,64/100-0,25

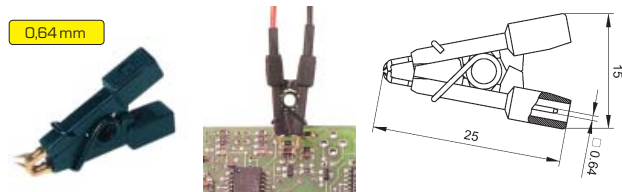


Part No.	Description
KLEPS 1 MICRO BK	Clamp-Type test probe SMD connector 0,64mm black
KLEPS 1 MICRO RD	Clamp-Type test probe SMD connector 0,64mm red

Part No.	Ord.No.
S KLEPS 1 MICRO BK	40191
S KLEPS 1 MICRO RD	45880

### MICRO-SMD CLIP 1

Spring-loaded, two-pole test clip, specially designed for SMD components. Gold-plated, hardened tip for testing circuits, flat-nosed grips for individual components; notch for gripping thin wires. Balanced spring force permits testing of large and small components; 0,64mm pin connection; electrically insulated spring. Connects with MKL 0,64/25-0,64 or MAL 4-0,64/100-0,25. Clamping range up to 8mm bolt diameter. Contact resistance 6mΩ, temperature range -30°C to +100°C.



Part No.	Description
MICRO-SMD CLIP 1	Two-pole test clip, 0,64 mm pin connection

Part No.	Ord.No.
S MICRO-SMD CLIP 1	50935

### KLEPS 2 Series

Miniature clamp-type test probe with solder connection. Gold-plated sprung bronze contact hook for wires up to a maximum diameter of 2mm. Remove actuator button for soldering, when cable is connected, press back on until it engages. Max. current 6A, contact resistance 15mΩ, temperature range -25°C to +100°C.



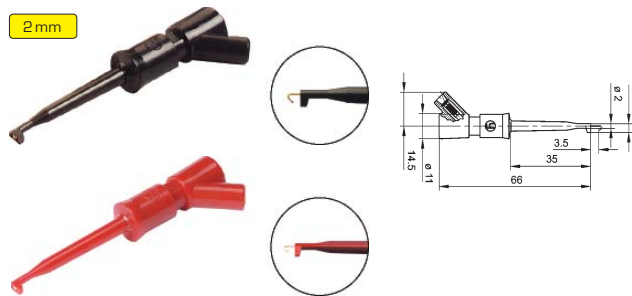
Part No.	Description
KLEPS 2 BK	Clamp-Type test probe, solderable 57,5mm black
KLEPS 2 RD	Clamp-Type test probe, solderable 57,5mm red

Part No.	Ord.No.
S KLEPS 2 BK	48534
S KLEPS 2 RD	48533

### KLEPS 2 BU Series

Miniature clamp-type test probe with 2mm diameter socket connection. Gold-plated copper beryllium contact spring. Gold-plated sprung bronze contact hook for wires up to a maximum diameter of 2mm. Suitable for connection to wrap posts up to a maximum of 1x1mm.

Max. current 6A, contact resistance 15mΩ, temperature range -25°C to +100°C.



Part No.	Description
KLEPS 2 BU BK	Clamp-Type test probe, socket 2mm 66mm black
KLEPS 2 BU RD	Clamp-Type test probe, socket 2mm 66mm red

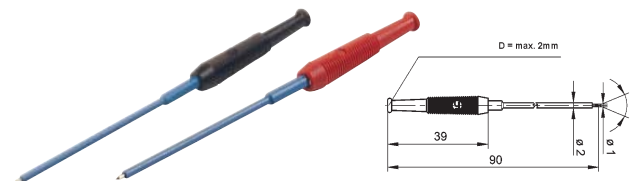
Part No.	Ord.No.
S KLEPS 2 BU BK	36587
S KLEPS 2 BU RD	36588

### PRUF 1 Series

Miniature test probe for sampling extremely small measuring points. Shatter-proof grip, may be unscrewed. The stainless steel tip easily penetrates insulation and oxide layers. Solder connection up to 0.5mm<sup>2</sup>.

Contact resistance 50mΩ

Temperature range -25°C to +60°C.



Part No.	Description
PRUF 1 BK	Miniature test probe solderable 90mm black
PRUF 1 RD	Miniature test probe solderable 90mm red

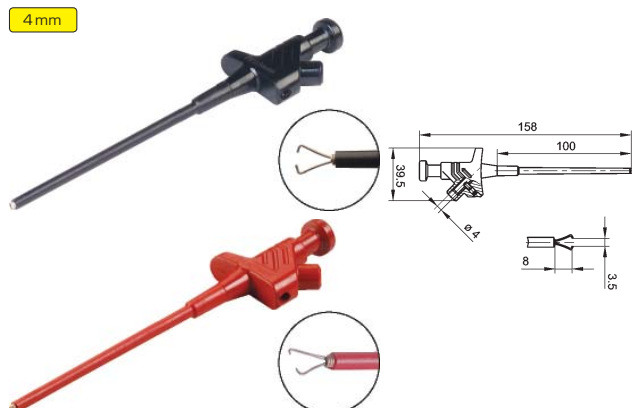
Part No.	Ord.No.
S PRUF 1 BK	36593
S PRUF 1 RD	36594

### KLEPS 30 Series

Clamp-type test probe with rotating grip jaws and flexible shaft. The special form of the grip jaws allows clamping of pins and wires up to a maximum of 4mm diameter. 4mm diameter brass socket connection with side screw, grip jaws additionally nickel-plated.

Contact resistance 50mΩ

Temperature range -25°C to +80°C.



Part No.	Description
KLEPS 30 BK	Clamp-Type test probe, socket 4mm 158mm black
KLEPS 30 RD	Clamp-Type test probe, socket 4mm 158mm red

Part No.	Ord.No.
S KLEPS 30 BK	36589
S KLEPS 30 RD	36590